Week 2-11

Thin Film Transistors 2

Ambipolar OTFTs Circuits and Frequency Response Noise Alternative Transistor Structures Phototransistors Morphology & Patterning Chapter 8.4-8.7



Ambipolar OTFTs

- Channel capable of supporting both electron and hole transport
- Advantage: Complementary logic possible with a single structure



Strategies for achieving bipolar action:

- Use material with both high μ_{FEn} and μ_{FEp} with contacts in the middle of the energy gap (i.e. use ambipolar conducting organics)
- Use a bilayer, one with higher electron vs. hole mobility and vice versa
- Use a blend of electron and hole transporting materials



Ambipolar transfer characteristics



Example: $V_{Tp} < V_{Tn}$

Linear regime

$$I_{D} = \frac{WC_{i}}{L} \mu_{FEn} \left(V_{GS} - V_{Tn} - \frac{V_{DS}}{2} \right) V_{DS}$$
$$\begin{pmatrix} 0 \le V_{DS} \le V_{DSsat} \\ V_{GS} > V_{Tn} \end{pmatrix}$$

Saturation regime

$$I_D = \frac{WC_i}{2L} \mu_{FEn} \left(V_{GS} - V_{Tn} \right)^2$$

 $\left(\begin{array}{c} V_{DS} \geq V_{GS} - V_{Tn} \\ V_{DS} \leq V_{GS} - V_{Tp} \end{array}\right)$

Ambipolar (quadratic) regime

$$I_{D} = \frac{WC_{i}}{2L} \left\{ \mu_{FEn} \left(V_{GS} - V_{Tn} \right)^{2} + \mu_{FEp} \left(V_{DS} - V_{GS} + V_{Tp} \right)^{2} \right\}$$
$$V_{DS} \ge V_{GS} - V_{Tn} \ge V_{GS}^{2} - V_{Tn}^{2}$$

on ratio of hole to electron μ_{FE}

The recombination point depends



 $V_{GS} = -15 V$ $V_{DS} = -10 V$ $V_{T} = 0 V$

(linear regime operation)



Schumechel et al. J. Appl. Phys. 98, 084511 (2005)

Bilayer ambipolar OTFT



Wang et al., Appl. Phys. Lett. 88, 133508 (2006)

5

Common Source Amplifier Circuit

Input DC bias point, AC input signal

Output will be DC bias point, AC output signal



Input/Output Characteristics

Relationship between V_{out} and V_{in}



Digital Complimentary Logic Circuit

Either one or the other transistor is ON at one time (never both) ⇒Only power dissipation is in switching logic state from ON to OFF



Digital Complimentary OTFT Circuit

Similar to CMOS technology in Si ICs Uses n- and p-channel OTFTs or Ambipolar Channels



Ring Oscillators can also Measure Frequency Response

For an odd number (N) of inverter gates, feedback is positive driving the circuit to oscillate

7 stage ring oscillator



Smith et al., Appl. Phys. Lett., 93, 253301 (2008)

Oscillation frequency a function of the delay per gate

$$2f_{osc} = 1/N\tau_{delay}$$
$$f_{delay} = (2\tau_{delay})^{-1} < f_T$$

Zschieschang, et al., 2013. Organic Electron., 14, 1516.



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Contributions to OTFT Noise

(See Ch. 7.1.1)

Noise quantified in terms of the mean square noise currents

 $S_{Itot} = \sum_{n} \left\langle i_n^2 \right\rangle$: S_{Itot} is the total noise spectral density

There are two white noise components due to channel Johnson (thermal) noise

$$S_{th} = \langle i_{th}^2 \rangle = 4k_B T g_0$$
 Channel conductance noise
 $S_{th} = \langle i_{th}^2 \rangle = \frac{8}{3} k_B T g_m$ Channel noise in saturation regime

An important noise in transistor is 1/f noise: this has a frequency dependence

Hooge's empirical formula

$$\frac{S_f}{I_D^2} = \frac{\left\langle i_f^2 \right\rangle}{I_D^2} = \frac{\alpha}{N f^{\gamma}}$$

 α = Hooge parameter (empirical) N = # carriers in channel $\gamma \sim 1$ (another empirical parameter)

Noise of a p-Channel OTFT in the Linear Regime



Noise Margin

To guarantee reliable switching,

LOW and HIGH inputs must be clearly distinguished by the circuit.



De Vusser, et al. IEEE Trans. Electron. Dev., 53, 601 (2006).

Dual gate transistors

- Useful for adjusting $V_{\scriptscriptstyle T}$ due to extra bias control of the second (bottom) gate
- In conventional CMOS technology, this is the "body potential"
- Important for controlling large ICs



Spijkman et al. Appl. Phys. Lett., 92 143304 (2008)

Dual gate control



Photograph of a 64-bit RFID transponder operating at 4.3 kb/s using dual gate inverter logic.

Myny et al. IEEE J. Sol. State Circuits, 46, 1223 (2011)

Improved noise margin Control of circuit gain

Spijkman et al. Appl. Phys. Lett., 92 143304 (2008)



Other Device Types V-gate transistor



Knife edge cuts through contact layers





Channel and gate insulator deposited

Vertical geometries reduce channel transit times \Rightarrow higher bandwidth Can be more compact than lateral OTFTs Can run in vertical mode (S=E₁, D=E₂) or horizontal mode (S=E₁, D=E₃) Stutzman, et al., Science, 299, 1881 (2003)



Permeable source transistor



Gate (separated from S by gate dielectric) controls S-D current by attraction or repulsion of charge emitted from S Operates similar to transistor in the triode mode (can have low g_O)

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Ben-Sasson et al., (2009). Appl. Phys. Lett., 95, 302.

Vertical Permeable Gate OTFT

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Vertical geometry ⇒short distance between emitter & collector ⇒potentially high frequency

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 Not shown in this particular device compared to conventional OTFTs

Klinger et al. (2017). Scientific Reports, 7, 44713.

Other Device Types Split gate transistor

- When gates shorted: ambipolar
- Otherwise, operated as p or n-channel





Phototransistors

- Changing the number of charges in the channel results in changing the drain current ⇒ gain
- Optical generation in a phototransistor is one such means
- While current gain can potentially be large, gain-bandwidth product limits frequency response
- An exciton dissociating junction needed to create the charge
- Possible charge generating mechanisms include exciton dissociation at:
 - contacts
 - traps at the insulator surface
 - ➢ field ionization



Phototransistor operating principles

Incident light generates charge, which changes the gate capacitance:

$$\Delta C_{GS} = \frac{\partial Q}{\partial V_{GS}} = q^2 \frac{\partial n_s}{\partial E_F}$$

This produces a gate photovoltage:

$$qV_{_{ph}}=\Delta E_{_F}$$

The photovoltage induces charge at the interface:

$$n_{T} = n_{0} \exp\left(q\Delta E_{F}/k_{B}T\right)$$

Which produces a photocurrent that adds to the dark current in the channel:

$$n_{T} = n_{ph} + n_{0} = \frac{(j_{ph} + j_{D})}{q\mu F}$$

Then: $V_{ph} = \frac{nk_{B}T}{q} \ln\left(\frac{j_{DT}}{j_{D}}\right) = \frac{nk_{B}T}{q} \ln\left(1 + \frac{j_{ph}}{j_{D}}\right)$ or: $V_{ph} = \frac{nk_{B}T}{q} \ln\left(1 + \frac{q\eta_{ext}\lambda P_{inc}}{j_{D}hc}\right)$

Finally yielding the channel photocurrent:

$$I_{ph} = g_m V_{ph} = \frac{g_m n k_B T}{q} \ln \left(1 + \frac{q \eta_{ext} \lambda P_{inc}}{j_D h c} \right)$$



Operating Characteristics of an OTFT



Noh, et al. Appl. Phys. Lett. 86, 043501 (2005)

OTFT With Exciton Dissociating HJ

Labram et al. Org. Electron. 11, 1250 (2010)

Morphology Determines OTFT Mobility

Highest mobilities when π -stacking is in the transistor plane

Different, common organic stacking motifs (see Chapter 2)

Structural Conformity Can Improve π-Stacking

Regiorandom alkane groups in this irregular arrangement leads to poor π -stacking \Rightarrow Low mobility between thiophene cores in adjacent molecules

Regioregularity leads to improved π -stacking \Rightarrow Improved mobility between thiophene cores

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Methods for Orienting the Channel Semiconductor

Materials, 22, 1005

Liu, et al., Z. (2009) Adv. Materials, 21, 1217

Solution Nozzle C18H27 supply (a) TTF-4SC18 Aligned layer Moving support 50 um (d)P 80 µm Miskiewicz, et al. (2006). Chem. Materials, 18, 4724. Organic Electronics Stephen R. Forrest Jang et al., (2012) Adv. Functional 26

zone casting

Morphologies Achieved by Drop Casting vs. **Solution Shearing PTDPPSe-Si**

- Drop cast films show some directionality
- Mobilities ~2X drop cast films

Lee et al., J. Am. Chem. Soc. 134, 20713 (2012)

Ink-Jet Printed Channels: Morphology Depends on Drying Dynamics

- Marangoni flow creates convection in two component solution
- Volatile component evaporates quickly at edges
- Can result in aligned molecular stacks forming a "coffee ring" pattern

Ink confined by choice of hydrophilic or hydrophobic surfaces on which it is deposited

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Sirringhaus et al. Science 290, 2123 (2000)